- 3. (currently amended) An X-ray microscope as claimed in Claim 1, wherein the cross-section of the fluid jet—(2) in the direction of the focused beam is smaller than that in the direction transversely thereof.
- 4. (currently amended) An X-ray microscope as claimed in Claim 1, wherein the fluid jet consists essentially mainly of liquid oxygen or nitrogen.
- 5. (currently amended) An X-ray microscope as claimed in Claim 1, wherein the means for producing a focused beam of electrically charged particles are formed by a standard comprises an electron gun for a cathode ray tube, the X-ray microscope also being provided with including a condenser lens (40) which is arranged disposed between the fluid jet (2) and the an object (14) to be imaged by means of the X-ray microscope.
- 6. (currently amended) An electron microscope which produces for producing a focused electron beam (6) and is provided with including a device for generating X-rays, characterized in that the said device including includes:
 - means for producing a fluid jet-(2),
 - means for directing the focus of the electron beam +€+ onto the fluid jet.
- 7. (currently amended) An electron microscope as claimed in Claim 6 which is provided with and including an X-ray microscope, and wherein the said device for generating X-rays acts acting as the X-ray source for the X-ray microscope.